



SHEET 1 OF 1

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LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Fuyuhiko INOUE, et al.

FILING DATE

February 25, 2002

GROUP

2877

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
12	AA	4,490,039	12/25/84	J. M. BRUCKLER, et al.			
12	AB	5,233,174	08/03/93	W. ZMEK			
12	AC	6,130,419	10/10/2000	D. R. NEAL			
12	AD	6,052,180	04/18/2000	D. R. NEAL			
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12	AF	6,184,974	02/06/2001	D. R. NEAL, et al.			
12	AG	5,864,381	01/26/99	D. R. NEAL, et al.			
12	AH	5,493,391	02/20/96	D. R. NEAL, et al.			
12	AI	5,978,085	11/02/99	A. H. SMITH, et al.			
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO	
12	AO	1 079 223	02/28/2001	EUROPE		
	AP					
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

12	AW	W. FREITAG, et al., JR, Insert, pages 8 -12, "WAVEFRONT ANALYSIS OF PHOTOLITHOGRAPHIC LENSES", January 1991
12	AX	T. NOGUCHI, et al., Publ. Natl. Astron. Obs. Japan, vol. 1, pages 49 - 55, "ACTIVE OPTICS EXPERIMENTS. 1." 1989
	AY	

Examiner

Michael Steffen

Date Considered

3-16-04

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.